## **Supporting Information**

## Reliable and stable ratiometric luminescent thermometer based on dual near-infrared emission in Cr<sup>3+</sup>-doped LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub> phosphor

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## Experimental details Synthesis

LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:Cr<sup>3+</sup> phosphors were prepared by conventional high-temperature solidstate reaction method. Stoichiometric amounts of La<sub>2</sub>O<sub>3</sub>, SrCO<sub>3</sub>, Ga<sub>2</sub>O<sub>3</sub>, and Cr<sub>2</sub>O<sub>3</sub> were weighed accurately and ground in an alumina mortar to form a homogeneous fine powder. The mixed powder was prefired at 900 °C in air for 2 h and cooled down to room temperature naturally. The pre-fired material was again ground to a fine powder. After that, the obtained powder was fired at 1400 °C for 6 h in air. After cooling down to room temperature naturally, the samples were ground again to acquire the final phosphors.

## Characterization

The XRD measurements were done on a DMAX-2500PC Powder X-ray diffractometer (normal scanning rate: 10°/min, 10–70°; parameters for refinement: 0.02° step size, 10 s counting time, 10–70°). The TOPAS academic software was used for crystal structure refinement. The morphology and energy-disperse X-ray spectroscopy (EDS) of the assynthesized phosphor were measured by a JSM-7800F field-emission scanning electron microscope (FE-SEM). The photoluminescence measurements were done using an FLS1000 spectrofluorometer (Edinburgh Instruments) loaded with a photomultiplier tube detector (PMT, 200–900 nm), and a 400 W Xe lamp was used as the excitation source. UH4150 spectrophotometer equipped with an integrating sphere was used to measure the diffuse reflection spectra. The low-temperature PL and PLE spectra (77 K) and temperature-dependent PL spectra (100–460 K range) were measured using an OptistatDN cryostat (Oxford Instruments) equipped with a MercuryiTC temperature-controlled system.



**Fig. S1** SEM image of the LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:3%Cr<sup>3+</sup> phosphor. The inset is particle size distributions of the phosphor.



**Fig. S2** Concentration-dependent emission spectra of LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:x%Cr<sup>3+</sup> (x = 0.5, 1, 3, 5, 7, and 10) phosphors under 420 nm excitation.



**Fig. S3** Decay curves of  $LaSr_2Ga_{11}O_{20}:Cr^{3+}$  phosphors under different  $Cr^{3+}$  doping concentrations under excitation at 420 nm, monitored at (a) 700 nm and (b) 750 nm, respectively. The upper inset is the dependence of the fluorescence lifetime on the  $Cr^{3+}$  concentration.



Fig. S4 Normalized photoluminescence and excitation spectra of  $LaSr_2Ga_{11}O_{20}$ :3%Cr<sup>3+</sup> phosphor at room temperature.



**Fig. S5** Excitation line of  $BaSO_4$  and emission spectrum of the  $LaSr_2Ga_{11}O_{20}:3\%Cr^{3+}$  phosphor collected using an integrating sphere. The inset shows a magnification of the emission spectrum.



**Fig. S6** (a) Temperature dependence of the PL intensity for both the  ${}^{2}E \rightarrow {}^{4}A_{2}$  and  ${}^{4}T_{2} \rightarrow {}^{4}A_{2}$  transitions and the overall PL intensity. (b) Spectral shift of the R<sub>1</sub>-line as a function of temperature in the 100–460 K range.



Fig. S7 Temperature dependence of thermal resolution  $\Delta T_{\min}$  in the range of linearity of the Boltzmann law.



**Fig. S8** (a) Demonstration of measuring the temperature of a metal block. The LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:3%Cr<sup>3+</sup> phosphor was placed at the surface of a metal block. The temperature of the metal block was adjusted by a temperature control device. After holding for 5 min at a certain temperature, the PL emission spectrum of the phosphor was recorded with a spectrofluorometer. (b) PL emission spectrum of the LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:3%Cr<sup>3+</sup> phosphor located on the surface when the metal block is heated to 383.5 K. (c) Test temperature of the metal block obtained by the  $I_T/I_E$  value from (b) and the plot of  $\ln(I_T/I_E)$  versus  $T^{-1}$  to calibrate the LaSr<sub>2</sub>Ga<sub>11</sub>O<sub>20</sub>:Cr<sup>3+</sup> Boltzmann optical thermometer.

| Sample                   | LaSr <sub>2</sub> Ga <sub>11</sub> O <sub>20</sub> :3%Cr <sup>3+</sup> |
|--------------------------|--|
| Space group              | I2/m   |
| a (Å)                    | 14.56872(17)   |
| b (Å)                    | 11.63243(13)   |
| c (Å)                    | 5.072881(58)   |
| α=γ (°)                  | 90   |
| β (°)                    | 91.260(2)  |
| Volume (Å <sup>3</sup> ) | 606.224(29)  |
| $R_{wp}$                 | 5.103%   |
| R <sub>p</sub>           | 3.511%   |
| R <sub>exp</sub>         | 0.723%   |

**Table S1** Rietveld refinement parameters of the  $LaSr_2Ga_{11}O_{20}:3\%Cr^{3+}$  phosphor.

**Table S2** Spectroscopic parameters of  $Cr^{3+}$  in  $LaSr_2Ga_{11}O_{20}$ .

| Spectroscopic parameters  | LaSr <sub>2</sub> Ga <sub>11</sub> O <sub>20</sub> :Cr <sup>3+</sup> |
|---|--|
| E( <sup>2</sup> E) (R-line energy)  | 14320 cm <sup>-1</sup> (corresponding to 698.3 nm)                   |
| $E({}^{4}T_{2})_{ZPL}(ZPL energy of {}^{4}T_{2})$                           | 14925 cm <sup>-1</sup>   |
| $E_{abs}({}^{4}T_{2})$ (absorption energy of ${}^{4}T_{2}$ )                | 16313 cm <sup>-1</sup> (corresponding to 613 nm)                     |
| $E_{Stokes}$ (Stokes shift of the ${}^{4}T_{2}$ - ${}^{4}A_{2}$ transition) | 2776 cm <sup>-1</sup>  |
| $\hbar\omega$ (phonon energy of ${}^{4}T_{2}$ )                             | 226 cm <sup>-1</sup>   |
| $S(^{4}T_{2})$ (Huang-Rhys parameter of $^{4}T_{2}$ )                       | 6.14   |
| Sħω   | 1388 cm <sup>-1</sup>  |